

Notice of References Cited	Application/Control No. 10/806,606	Applicant(s)/Patent Under Reexamination NAKAI, EIJI	
	Examiner DANIEL TEKLE	Art Unit 2621	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0126993	09-2002	Sakuramoto et al.	386/77
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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